## Notice of References Cited Application/Control No. 10/566,224 Examiner ANOOP SINGH Applicant(s)/Patent Under Reexamination FUJII ET AL. Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	В	US-			
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	D	US-			
	Е	US-			
	F	US-			
	G	US-			
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	K	US-			
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## **NON-PATENT DOCUMENTS**

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*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)						
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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